

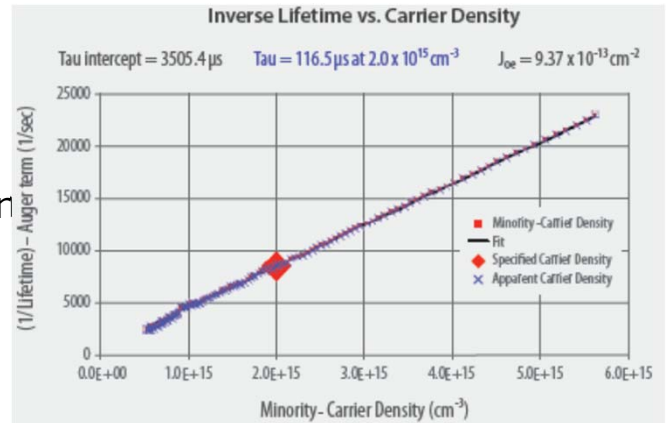


WCT-120
WCT-120 MX
少子寿命检测仪

Best available calibrated measurement of carrier recombination lifetime. Widely used for both monocrystalline and multicrystalline silicon wafers.

量测功能:

- Lifetime
- Resistivity
- Emitter saturation current density
- Trap density
- One-sun Voc



少子寿命量测模式:

QSSPC, Transient, and Generalized Lifetime Analysis

Sinton少子寿命分析仪依据校准后的光导变化量及可追溯光强激发条件, 量测得到具有物理意义正确数据

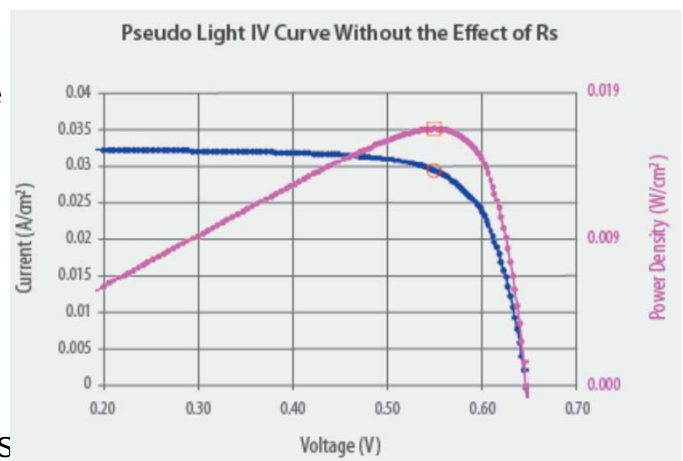


Suns-Voc
Suns-Voc MX
电池片IV曲线分析仪

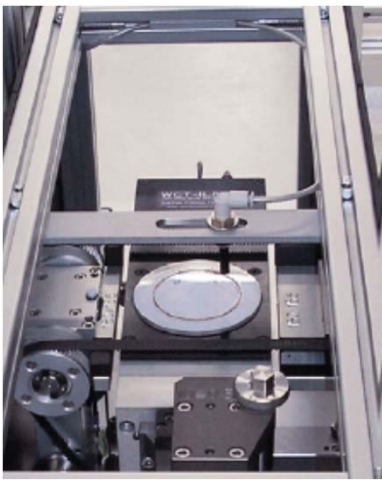
Perfect for paste-firing optimization and process control. Open-circuit method indicates the upper bound for any solar cell precursors after junction formation.

量测参数:

- Implied I-V curve at open circuit : materials limit to efficiency
- Pseudo-efficiency
- Pseudo-fill-factor
- Two-diode analysis
- Shunt value



Suns-Voc显示光照下的近似IV曲线(不考虑 R_s 影响)



WCT-IL800
在线检测

Fast inline testing with no compromises. Monitor wafer lifetime, sheet resistance and trapping with the comprehensive accuracy of an offline tool and an optimized industrial software package.

应用范例:

- 硅片进料检验, 少子寿命, 片电阻
- 监控磷扩散品质
- 早期发现各制程所引入杂质污染
- 保证氮化制程最佳钝化效果

量测参数:

少子寿命, 片电阻, 发射极饱和电流, 80mm 传感器, >1800 wph



FCT-350
高效率电池片检测仪

Advanced analysis of solar cells and modules including light I-V and Suns-voc data. Capability to accurately measure high-efficiency conventional or backside-contact solar cells and modules. One-sun or concentrator instruments available.

分析技术:

- Suns-Voc曲线
- Suns-Voc, Jsc, V_{load} 三点测试
- 不同光强综合IV曲线
- 光强vs效率特性曲线



BLS-1/BCT-400
硅块体寿命分析仪

Simple and accurate contactless measurement of true bulk lifetimes on as-grown or shaped silicon.

主要应用:

- 检验高纯度硅1-5ms寿命
- 检验B-Cz原生硅, 无须表面处理
- 分析多晶硅块寿命及陷井浓度
- 检查B-O缺陷, Fe杂质, 表面损伤
- 监控Cz, FZ, 多晶硅, UMG硅材料品质

量测参数:

少子寿命, 电阻率, 45x15mm传感器
白光及IR激发, 3mm量测深度

